



□ 1,229,994 documents online



Welcome to IEEE Xplore

... delivering full text access to the world's highest quality technical literature in electrical engineering, computer science, and electronics.

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

BROWSE

SEARCH

IEEE XPLORE GUIDE

Browse

- » [Journals & Magazines](#)
- » [Conference Proceedings](#)
- » [Standards](#)
- » [Books](#)

Basic Search

-
- >>**
-
- (All Fields)
- » [Advanced Search](#)
 - » [Author Search](#)
 - » [CrossRef Search](#)

Content Updates

Browse the latest update to see recently added content.

- » [Latest Content Update](#)

Alerts

Register and access your tables of contents alerts.

- » [Visit Alerts](#)

Top 100 Documents

Find out the most accessed documents for the month.

- » [View Top 100](#)

Books

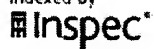
IEEE books are available for purchase from Wiley and Wiley-IEEE C Press.

- » [Find out more](#)
- » [Browse Books](#)



Cookies Enabled

Indexed by



[Help](#) [Contact Us](#) [Privacy & :](#)

© Copyright 2005 IEEE –



Welcome United States Patent and Trademark Office

[Search Session History](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Mon, 31 Oct 2005, 3:51:10 PM EST

Edit an existing query or
compose a new query in the
Search Query Display.

Search Query Display

Select a search number (#)
to:

- Add a query to the Search Query Display
- Combine search queries using AND, OR, or NOT
- Delete a search
- Run a search

Recent Search Queries

- | | |
|---------------------|--|
| #1 | ((autoregressive model)<in>metadata) |
| #2 | ((autoregressive model)<in>metadata) |
| #3 | ((autoregressive model)<in>metadata) |
| #4 | ((autoregressive model)<in>metadata) |
| #5 | ((autoregressive model)<in>metadata) |
| #6 | ((autoregressive model)<in>metadata) |
| #7 | ((autoregressive model)<in>metadata) |
| #8 | ((autoregressive model)<in>metadata) |
| #9 | ((autoregressive model)<in>metadata) |
| #10 | ((((autoregressive model)<in>metadata))<AND>(outlier<in>metadata)) |
| #11 | ((((autoregressive model)<in>metadata))<AND>(outlier<in>metadata)) |
| #12 | ((((autoregressive model)<in>metadata))<AND>(outlier<in>metadata)) |

Indexed by
 Inspec

[Help](#) [Contact Us](#) [Privacy & :](#)

© Copyright 2005 IEEE –


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#)

Welcome United States Patent and Trademark Office

☐ Author Search
[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)**OPTION 1****Quick Find an Author:**

Enter a name to locate articles written by that author.

Example: Enter Lockett S to obtain a list of authors with the last name Lockett and the first initial S.

**OPTION 2****Browse alphabetically**

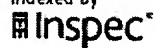
Select a letter from the list.

[A](#) [B](#) [C](#) [D](#) [E](#) [F](#) [G](#) [H](#) [I](#) [J](#) [K](#) [L](#) [M](#) [N](#) [O](#) [P](#) [Q](#) [R](#) [S](#) [T](#) [U](#) [V](#) [W](#) [X](#) [Y](#) [Z](#)

Select a name to view articles written by that author

[Takeuchi A.](#)[Takeuchi A. Y.](#)[Takeuch](#)[Takeuchi E.](#)[Takeuchi E. S.](#)[Takeuch](#)[Takeuchi G.](#)[Takeuchi H.](#)[Takeuch](#)[Takeuchi J.](#)[Takeuchi J. -I.](#)[Takeuch](#)[Takeuchi K.](#)[Takeuchi L.](#)[Takeuch](#)[Takeuchi M.](#)[Takeuchi N.](#)[Takeuch](#)[Takeuchi R.](#)[Takeuchi S.](#)[Takeuch](#)[Takeuchi V.](#)[Takeuchi W.](#)[Takeuch](#)

Indexed by


[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

[Search Results](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "(takeuchi j.<in>au)"

Your search matched **22** of **1253851** documents. [e-mail](#)A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» Search Options

[View Session History](#)[New Search](#)

Modify Search

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL	IEEE Journal or Magazine
IEE JNL	IEE Journal or Magazine
IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

Select Article Information

- ☐ 1. **Study on the interchangeability of the VCR**
Takeuchi, J.; Okuda, M.; Sakumoto, H.;
Consumer Electronics, IEEE Transactions on
Volume 37, Issue 4, Nov. 1991 Page(s):800 - 805
Digital Object Identifier 10.1109/30.106942
[AbstractPlus](#) | Full Text: [PDF](#)(380 KB) IEEE JNL
- ☐ 2. **Photomultiplier tube of new dynode configuration**
Kyushima, H.; Hasegawa, Y.; Atsumi, A.; Nagura, K.; Yokota, H.; Ito, M.; Takei
Matsuura, H.; Suzuki, S.;
Nuclear Science, IEEE Transactions on
Volume 41, Issue 4, Part 1-2, Aug 1994 Page(s):725 - 729
Digital Object Identifier 10.1109/23.322796
[AbstractPlus](#) | Full Text: [PDF](#)(276 KB) IEEE JNL
- ☐ 3. **A study on the interchangeability of the center-rotating drum VCR**
Takeuchi, J.; Koga, A.; Kozai, T.;
Consumer Electronics, IEEE Transactions on
Volume 41, Issue 4, Nov. 1995 Page(s):979 - 985
Digital Object Identifier 10.1109/30.477214
[AbstractPlus](#) | Full Text: [PDF](#)(528 KB) IEEE JNL
- ☐ 4. **Characterization of the Bayes estimator and the MDL estimator for expon**
Takeuchi, J.;
Information Theory, IEEE Transactions on
Volume 43, Issue 4, July 1997 Page(s):1165 - 1174
Digital Object Identifier 10.1109/18.605579
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(688 KB) IEEE JNL
- ☐ 5. **/spl alpha/-parallel prior and its properties**
Takeuchi, J.; Amari, S.;
Information Theory, IEEE Transactions on
Volume 51, Issue 3, March 2005 Page(s):1011 - 1023
Digital Object Identifier 10.1109/TIT.2004.842703
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(376 KB) IEEE JNL
- ☐ 6. **A chat information service system using a humanoid robot**

Hoshino, A.; Kato, K.; Takeuchi, J.; Tsujino, H.;
Robot and Human Interactive Communication, 2005. ROMAN 2005. IEEE Inte
Workshop on
Aug. 13 - 15 2005 Page(s):468 - 473
[AbstractPlus](#) | Full Text: [PDF\(831 KB\)](#) IEEE CNF

7. **Regent Developments in Microwave Slot-Line Mixers and Frequency Multi**
Hunton, J.K.; Takeuchi, J.S.;
Microwave Symposium Digest, G-MTT International
Volume 70, Issue 1, May 1970 Page(s):196 - 199
[AbstractPlus](#) | Full Text: [PDF\(456 KB\)](#) IEEE CNF

8. **Turbulent velocity profile measurement in circular pipe flow using particle velocimetry technique**
Takeuchi, J.; Miraghaie, R.; Yuki, K.; Satake, S.; Kunugi, T.; Morley, N.B.;
Fusion Engineering, 2003. 20th IEEE/NPSS Symposium on
14-17 Oct. 2003 Page(s):140 - 143
Digital Object Identifier 10.1109/FUSION.2003.1426607
[AbstractPlus](#) | Full Text: [PDF\(1697 KB\)](#) IEEE CNF

9. **A simulation study of the simplest adaptive virtual animal learning model classification and integration networks**
Takeuchi, J.; Yamada, H.; Ichikawa, M.;
Neural Information Processing, 2002. ICONIP '02. Proceedings of the 9th Inter
Conference on
Volume 5, 18-22 Nov. 2002 Page(s):2571 - 2574 vol.5
Digital Object Identifier 10.1109/ICONIP.2002.1201959
[AbstractPlus](#) | Full Text: [PDF\(446 KB\)](#) IEEE CNF

10. **A flying object using hardware implemented, vision processing and motion system with adaptive neural network**
Yamada, H.; Takeuchi, J.; Matsumoto, G.; Ichikawa, M.;
Neural Information Processing, 2002. ICONIP '02. Proceedings of the 9th Inter
Conference on
Volume 2, 18-22 Nov. 2002 Page(s):685 - 690 vol.2
Digital Object Identifier 10.1109/ICONIP.2002.1198145
[AbstractPlus](#) | Full Text: [PDF\(448 KB\)](#) IEEE CNF

11. **Asymptotically minimax regret by Bayes mixtures**
Takeuchi, J.; Barron, A.R.;
Information Theory, 1998. Proceedings. 1998 IEEE International Symposium on
16-21 Aug. 1998 Page(s):318
Digital Object Identifier 10.1109/ISIT.1998.708923
[AbstractPlus](#) | Full Text: [PDF\(96 KB\)](#) IEEE CNF

12. **Mixture models achieving optimal coding regret**
Barron, A.R.; Takeuchi, J.;
Information Theory Workshop, 1998
22-26 June 1998 Page(s):16
Digital Object Identifier 10.1109/ITW.1998.706377
[AbstractPlus](#) | Full Text: [PDF\(48 KB\)](#) IEEE CNF

13. **A low power and compact desktop ATM PMD**
Wakayama, Y.; Nakano, F.; Takeuchi, J.; Honda, N.; Ishii, K.; Sakamoto, T.; F
Custom Integrated Circuits Conference, 1997., Proceedings of the IEEE 1997
5-8 May 1997 Page(s):331 - 334
Digital Object Identifier 10.1109/CICC.1997.606641
[AbstractPlus](#) | Full Text: [PDF\(468 KB\)](#) IEEE CNF

- 14. **The development and the study of R5900-00-M64 for scintillating/optical**
 Yoshizawa, Y.; Ohtsu, H.; Ota, N.; Watanabe, T.; Takeuchi, J.;
 Nuclear Science Symposium, 1997. IEEE
 9-15 Nov. 1997 Page(s):877 - 881 vol.1
 Digital Object Identifier 10.1109/NSSMIC.1997.672721
[AbstractPlus](#) | Full Text: [PDF](#)(340 KB) IEEE CNF
- 15. **Approximation of Bayes code for Markov sources**
 Takeuchi, J.; Kawabata, T.;
 Information Theory, 1995. Proceedings., 1995 IEEE International Symposium
 17-22 Sept. 1995 Page(s):391
 Digital Object Identifier 10.1109/ISIT.1995.550378
[AbstractPlus](#) | Full Text: [PDF](#)(116 KB) IEEE CNF
- 16. **Characterization of the Bayes estimator and the MDL estimator for expon**
 Takeuchi, J.-I.;
 Information Theory, 1995. Proceedings., 1995 IEEE International Symposium
 17-22 Sept. 1995 Page(s):228
 Digital Object Identifier 10.1109/ISIT.1995.535743
[AbstractPlus](#) | Full Text: [PDF](#)(108 KB) IEEE CNF
- 17. **A study on the interchangeability of the center-rotating drum VCR**
 Takeuchi, J.; Koga, A.; Kozai, T.;
 Consumer Electronics, 1995., Proceedings of International Conference on
 7-9 June 1995 Page(s):28 - 29
[AbstractPlus](#) | Full Text: [PDF](#)(136 KB) IEEE CNF
- 18. **Chip on glass technology for large capacity and high resolution LCD**
 Masuda, M.; Sakuma, K.; Satoh, E.; Yamasaki, Y.; Miyasaka, H.; Takeuchi, J.;
 Electronic Manufacturing Technology Symposium, 1989, Proceedings. Japan I
 Symposium, Sixth IEEE/CHMT International
 26-28 April 1989 Page(s):55 - 58
 Digital Object Identifier 10.1109/IEMTS.1989.76109
[AbstractPlus](#) | Full Text: [PDF](#)(228 KB) IEEE CNF
- 19. **Photomultiplier Tube Of New Dynode Configuration**
 Kyushima, H.; Hasegawa, Y.; Atsumi, A.; Nagura, K.; Yokota, H.; Ito, M.; Take
 Matsuura, H.; Suzuki, S.;
 Nuclear Science Symposium and Medical Imaging Conference, 1993., 1993 IE
 Record.
 31 Oct.-6 Nov. 1993 Page(s):709 - 713
[AbstractPlus](#) | Full Text: [PDF](#)(260 KB) IEEE CNF
- 20. **Antiferromagnetism of a conductive polymer AlPeF-Br/sub 4/**
 Hiromitsu, I.; Takeuchi, J.; Ito, T.;
 Science and Technology of Synthetic Metals, 1994. ICSM '94. International Cc
 July 24-29, 1994 Page(s):486 - 486
[AbstractPlus](#) | Full Text: [PDF](#)(202 KB) IEEE CNF
- 21. **Metal package photomultiplier tube**
 Kyushima, H.; Hasegama, Y.; Atsumi, A.; Yokota, Y.; Matsuura, H.; Watase, Y
 Takeuchi, J.; Oba, K.;
 Instrumentation and Measurement Technology Conference, 1994. IMTC/94. C
 Proceedings. 10th Anniversary. Advanced Technologies in I & M., 1994 IEEE
 10-12 May 1994 Page(s):242 - 245 vol.1
 Digital Object Identifier 10.1109/IMTC.1994.352082
[AbstractPlus](#) | Full Text: [PDF](#)(276 KB) IEEE CNF

22. **Neuro-computational approaches to the FEM based electrical impedance problems**

Takeuchi, J.; Kosugi, Y.;

Systems, Man, and Cybernetics, 1994. 'Humans, Information and Technology' International Conference on

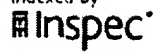
Volume 3, 2-5 Oct. 1994 Page(s):2284 - 2289 vol.3

Digital Object Identifier 10.1109/ICSMC.1994.400205

[AbstractPlus](#) | Full Text: [PDF](#)(460 KB) IEEE CNF



Indexed by



[Help](#) [Contact Us](#) [Privacy & :](#)

© Copyright 2005 IEEE –

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#)

Welcome United States Patent and Trademark Office

☐ Author Search[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)**OPTION 1****Quick Find an Author:**

Enter a name to locate articles written by that author.

Example: Enter Lockett S to obtain a list of authors with the last name Lockett and the first initial S.

Select a name to view articles written by that author

[Yamanishi A.](#)[Yamanishi H.](#)[Yamanis](#)[Yamanishi M.](#)[Yamanishi N.](#)[Yamanis](#)[Yamanishi Y.](#)**OPTION 2****Browse alphabetically**

Select a letter from the list.

[A](#) [B](#) [C](#) [D](#) [E](#) [F](#) [G](#) [H](#) [I](#) [J](#) [K](#) [L](#) [M](#) [N](#) [O](#) [P](#) [Q](#) [R](#) [S](#) [T](#) [U](#) [V](#) [W](#) [X](#) [Y](#) [Z](#)

Indexed by

[Help](#) [Contact Us](#) [Privacy &](#)

© Copyright 2005 IEEE


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

☐ Search Results

BROWSE

SEARCH

IEEE XPLORE GUIDE

Results for "(yamanishi k.<in>au)"

Your search matched **11** of **1253851** documents.

e-mail

A maximum of **100** results are displayed, **25** to a page, sorted by **Relevance** in **Descending** order.

» Search Options

[View Session History](#)
[New Search](#)

Modify Search


☐ Check to search only within this results set
Display Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

Select Article Information

- ☐ **1. Recording characteristics of electroless-plated perpendicular media for**
 Osaka, T.; Matsubara, H.; Yamanishi, K.; Mizutani, H.; Okabe, H.;
 Magnetics, IEEE Transactions on
 Volume 23, Issue 3, May 1987 Page(s):1935 - 1936
[AbstractPlus](#) | Full Text: [PDF](#)(232 KB) IEEE JNL
- ☐ **2. The effects of underlayer on recording characteristics of electroless plate recording flexible media**
 Osaka, T.; Matsubara, H.; Yamanishi, K.; Mizutani, H.; Goto, F.;
 Magnetics, IEEE Transactions on
 Volume 23, Issue 5, Sep 1987 Page(s):2356 - 2358
[AbstractPlus](#) | Full Text: [PDF](#)(384 KB) IEEE JNL
- ☐ **3. A decision-theoretic extension of stochastic complexity and its applicat**
 Yamanishi, K.;
 Information Theory, IEEE Transactions on
 Volume 44, Issue 4, July 1998 Page(s):1424 - 1439
 Digital Object Identifier 10.1109/18.681319
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(928 KB) IEEE JNL
- ☐ **4. Capture rate enhance method of 0.1-μm level defects by pattern-matching**
 Sakurai, K.; Onoyama, A.; Ishii, H.; Oka, K.; Yamanishi, K.;
 Semiconductor Manufacturing, IEEE Transactions on
 Volume 13, Issue 4, Nov. 2000 Page(s):434 - 441
 Digital Object Identifier 10.1109/66.892629
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(192 KB) IEEE JNL
- ☐ **5. Mining open answers in questionnaire data**
 Yamanishi, K.; Hang Li;
 Intelligent Systems, IEEE [see also IEEE Intelligent Systems and Their Applica
 Volume 17, Issue 5, Sep/Oct 2002 Page(s):58 - 63
 Digital Object Identifier 10.1109/MIS.2002.1039833
[AbstractPlus](#) | Full Text: [PDF](#)(465 KB) IEEE JNL
- ☐ **6. Solution of pattern matching inspection problem for grainy metal layers**
 Sakurai, K.; Onoyama, A.; Fujii, T.; Yamanishi, K.; Fujii, S.; Morita, H.;
 Semiconductor Manufacturing, IEEE Transactions on

Volume 15, Issue 1, Feb. 2002 Page(s):118 - 126

Digital Object Identifier 10.1109/66.983451

[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(197 KB) IEEE JNL

7. **Dynamic model selection with its applications to computer security**
Maruyama, Y.; Yamanishi, K.;
Information Theory Workshop, 2004. IEEE
24-29 Oct. 2004 Page(s):82 - 87
Digital Object Identifier 10.1109/ITW.2004.1405279
[AbstractPlus](#) | Full Text: [PDF](#)(697 KB) IEEE CNF
8. **Solution of in-line inspection problem for grainy metal layers by "saturation grayscale"**
Onoyama, A.; Sakurai, K.; Fujii, T.; Oka, K.; Yamanishi, K.;
Semiconductor Manufacturing, 2000. Proceedings of ISSM 2000. The Ninth International Symposium on
26-28 Sept. 2000 Page(s):203 - 206
Digital Object Identifier 10.1109/ISSM.2000.993649
[AbstractPlus](#) | Full Text: [PDF](#)(435 KB) IEEE CNF
9. **Capture rate enhancement method of 0.1 μm -level defects by pattern mat**
Sakurai, K.; Onoyama, A.; Ishii, H.; Oka, K.; Yamanishi, K.;
Semiconductor Manufacturing Conference Proceedings, 1999 IEEE International
11-13 Oct. 1999 Page(s):131 - 134
Digital Object Identifier 10.1109/ISSM.1999.808755
[AbstractPlus](#) | Full Text: [PDF](#)(284 KB) IEEE CNF
10. **A defect-situation forecasting technology to optimize future DRAM-reduction**
Sakurai, K.; Shimada, Y.; Yamanishi, K.;
Semiconductor Manufacturing Conference Proceedings, 1997 IEEE International
6-8 Oct. 1997 Page(s):E43 - E46
Digital Object Identifier 10.1109/ISSM.1997.664589
[AbstractPlus](#) | Full Text: [PDF](#)(336 KB) IEEE CNF
11. **Protein alpha-helix region prediction based on stochastic-rule learning**
Mamitsuka, H.; Yamanishi, K.;
System Sciences, 1993, Proceedings of the Twenty-Sixth Hawaii International Conference on
Volume i, 5-8 Jan 1993 Page(s):659 - 668 vol.1
Digital Object Identifier 10.1109/HICSS.1993.270675
[AbstractPlus](#) | Full Text: [PDF](#)(858 KB) IEEE CNF

